

Integrated Device Technology, Inc. 6024 Silver Creek Valley Road, San Jose, CA - 95138

# PRODUCT/PROCESS CHANGE NOTICE (PCN)

					0 11 01	• • • • • • • • • • • • • • • • • • • •	
PCN #: <b>A190</b>	2-03	DATE:	12-Mar-2019	MEANS OF DIS	STINGUISHING CH	IANGED DEVICES:	
Product Affected	4RCD0124KC0AT 4RCD0124KC0AT 4RCD0124KC0AT 4RCD0124KC0AT	GI(8) G8/B		☐ Product Marl ■ Back Mark □ Date Code □ Other	Lot # will nave:	ASECL, Taiwan	
Date Effective:	12-Jun-2019						
Contact:	IDT PCN DESK			Attachment:	Yes	□ No	
E-mail:	pcndesk@idt.com				e contact your local s le request.	ales representative for	
DESCRIPTION	AND PURPOSE OF C	HANGE:					
<ul> <li>□ Die Technolog</li> <li>□ Wafer Fabrica</li> <li>□ Assembly Prod</li> <li>□ Equipment</li> <li>■ Material</li> <li>□ Testing</li> <li>■ Manufacturing</li> <li>□ Data Sheet</li> <li>□ Other</li> </ul>	cess	This notification is to advise our customers that IDT is adding ASECL as an alternate assembly facility.  There is no change to the moisture performance.  Attachment I details the qualification results.					
	QUALIFICATION SU ation data shown in Atta		:				
IDT records indited to grant approval it will be assume IDT reserves the	cate that you require writed or request additional in that this change is according to ship either versusion has been depleted.	itten notification.	cation of this cha If IDT does not	receive acknowle	edgement within 30 d	ays of this notice	
Customer:			_ ⊏	] Approval f	for shipments pric	or to effective date.	
Name/Date:			E-	-Mail Address:			
Title: P			Pł	Phone# /Fax# :			
CUSTOMER CO	OMMENTS:						
IDT ACKNOW	LEDGMENT OF REC	EIPT:					
RECD. BY:				DATE:			

## PRODUCT/PROCESS CHANGE NOTICE (PCN)

#### **ATTACHMENT I - PCN # : A1902-03**

**PCN Type:** Manufacturing Site - Alternate Assembly Location

**Data Sheet Change:** None

No change in moisture sensitivity level (MSL)

#### **Detail Of Change:**

This notification is to advise our customers that IDT is adding ASECL as an alternate assembly facility.

The material set details of the current and alternate assembly location is as shown in Table 1.

There is no change to the moisture performance.

Table 1: Assembly Material Sets for The Existing and Alternate Assembly Location

	Existing Assembly (Amkor, Philippines)	Existing Assembly (ASEK, Taiwan)	Alternate Assembly (ASECL, Taiwan)	
Die Bump	Sn1.8Ag	Sn1.8Ag	Sn1.8Ag	
Mold Compound	GE100-RFC32	KE-G1250FC-20B	KE-G1250FC-20B	
Substrate	UMTC E700/AUS703	UMTC E700/AUS703 Kinsus E700/AUS703	UMTC E700/AUS703 Kinsus E700/AUS703	
Solder Balls	Sn96.5/Ag3.0/Cu0.5	Sn96.5/Ag3.0/Cu0.5	Sn96.5/Ag3.0/Cu0.5	

## PRODUCT/PROCESS CHANGE NOTICE (PCN)

#### **ATTACHMENT I - PCN # : A1902-03**

### **Qualification Information and Qualification Data:**

**Affected Packages:** FCCSP-253

**Assembly Material:** Shown on page 2 of this attachment.

**Qual Plan & Results:** Tests are in accordance with JEDEC47 recommended tests.

**Qualification Vehicle:** FCCSP-253

Test Description	Test Method	Test Results (Rej / SS)			
Test Description	Test Method	Lot 1	Lot 2	Lot 3	
* Temperature Cycling (-55°C to 125°C, 700 cycles)	JESD22-A104	0/25	0/25	0/25	
* HAST - biased (130 °C/85% RH, 96 Hrs)	JESD22-A110	0/25	0/25	0/25	
High Temperature Storage Bake (150°C, 1000 Hrs)	JESD22-A103	0/25	0/25	0/25	
Solder Ball Shear Test	JESD22-B117	0/5	0/5	0/5	
Moisture Sensitivity Level, MSL	J-STD-20 / MSL 3, 260 °C	0/25	0/25	-	

<sup>\*</sup> Tests were subjected to Preconditioning per JESD22-A113 prior to stress test